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Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China







Power MOSFET

20 V, 5.8 A/4.6 A Dual N-Channel, DFN6 3x3 mm Package

Features

- Exposed Drain Package
- Excellent Thermal Resistance for Superior Heat Dissipation
- Low Threshold Levels
- Low Profile (< 1 mm) Allows It to Fit Easily into Extremely Thin Environments
- This is a Pb-Free Device

Applications

- DC-DC Converters (Buck and Boost Circuits)
- Power Supplies
- Hard Disk Drives

MOSFET I MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Param	Symbol	Value	Unit		
Drain-to-Source Voltag	je		V_{DSS}	20	V
Gate-to-Source Voltag	е		V_{GS}	±20	V
Continuous Drain	Steady	T _A = 25°C	I _D	4.3	Α
Current (Note 1)	State	T _A = 85°C		3.0	
	t ≤ 5.0 s	T _A = 25°C		5.8	
Power Dissipation (Note 1)	Steady State T _A = 25°C		P _D	1.74	W
Pulsed Drain Current	I _{DM}	17.2	Α		
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to 150	°C
Source Current (Body D	I _S	1.6	Α		
Lead Temperature for S (1/8" from case for 10 s		urposes	TL	260	°C

MOSFET II MAXIMUM RATINGS (T_{.I} = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltag	je		V_{DSS}	20	V
Gate-to-Source Voltag	е		V_{GS}	±12	V
Continuous Drain	Steady	T _A = 25°C	I _D	3.6	Α
Current (Note 1)	State	T _A = 85°C		2.5	
	t ≤ 5.0 s	$T_A = 25^{\circ}C$		4.6	
Power Dissipation (Note 1)	Steady State	T _A = 25°C	P_D	1.74	W
Pulsed Drain Current t ≤10 μs			I _{DM}	13.8	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to 150	°C
Source Current (Body Diode)			I _S	1.7	Α
Lead Temperature for S (1/8" from case for 10 s		urposes	T _L	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces)
- Surface Mounted on FR4 Board using the minimum recommended pad size of 30 mm², 1 oz. Cu



ON Semiconductor®

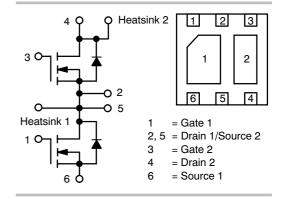
http://onsemi.com

MOSFET I

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
20 V	60 mΩ @ 4.5 V	5.8 A

MOSFET II

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
20 V	90 m Ω @ 4.5 V	4.6 A



MARKING DIAGRAMS



DFN6 CASE 506AG



3502 = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping [†]
NTLGD3502NT1G	DFN6 (Pb-free)	3000/Tape & Reel
NTLGD3502NT2G	DFN6 (Pb-free)	3000/Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{ hetaJA}$	72	°C/W
Junction-to-Ambient $-t \le 5$ s (Note 1)	$R_{ heta JA}$	40]
Junction-to-Ambient - Steady State min Pad (Note 2)	$R_{ heta JA}$	110	
Junction-to-Ambient - Pulsed (25% duty cycle) min Pad (Note 2)	$R_{ hetaJA}$	60	

MOSFET I ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition	ons	Min	Тур	Max	Unit
Off Characteristics							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_D = 250 μA		20			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J	I _D = 250 μA, ref to	o 25°C		10		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 16 V	$T_J = 25^{\circ}C$			1.0	μΑ
			T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	±20 V			±100	nA
On Characteristics (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 1$	250 μΑ	1.0	1.7	2.0	٧
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-4.4		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 4.5 V, I _D =	= 4.3 A		50	60	mΩ
Forward Transconductance	9 _{FS}	V _{DS} = 10 V, I _D =	= 4.0 A		5.9		S
Charges, Capacitances & Gate Resi	stance					-	
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 10 V			250	480	pF
Output Capacitance	C _{OSS}	1			138	200	1
Reverse Transfer Capacitance	C _{RSS}				52	90	
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 10$	V; I _D = 4.3 A		2.9	4.0	nC
Gate-to-Source Charge	Q_{GS}	(Note 3)			1.0		
Gate-to-Drain Charge	Q_{GD}	1			1.1		
Gate Resistance	R_{G}				1.5		Ω
Switching Characteristics, V _{GS} = 4.5	5 V (Note 4)				•		•
Turn-On Delay Time	t _{d(ON)}	V _{GS} = 4.5 V, V _{DD}			7.0	12	ns
Rise Time	t _r	I _D = 4.3 A, R _G =	: 10 Ω		17.5	25	
Turn-Off Delay Time	t _{d(OFF)}				8.6	15	
Fall Time	t _f				3.3	5.0	1
Drain-Source Diode Characteristics	- ' }					1	
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V, I _S = 1.6 A T _J = 25°C			0.78	1.2	V
			T _J = 125°C		0.63		1
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V}, d_{ISD}/d_t =$	100 A/μs,		16.7		ns
Charge Time	t _a	I _S = 1.0 A			8.2		1
Discharge Time	t _b	1			8.5		1
Reverse Recovery Charge	Q _{RR}	1			7.0		nC

^{3.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2% 4. Switching characteristics are independent of operating junction temperatures

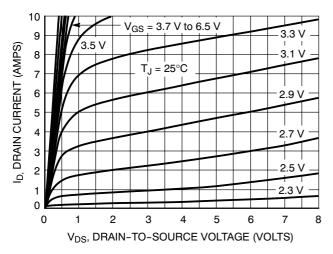
$\textbf{MOSFET II ELECTRICAL CHARACTERISTICS} \ (T_J = 25^{\circ}\text{C unless otherwise noted})$

Parameter	Symbol	Test Condition	ons	Min	Тур	Max	Unit
Off Characteristics							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_D = 250 μA		20			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J	I _D = 250 μA, ref t	o 25°C		22		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 16 V	$T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$			1 10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	1 -			±100	nA
On Characteristics (Note 5)	1				l.	1	1
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	250 μΑ	0.6		2.0	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J		<u> </u>		-2.8		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 4.5 V, I _D :	= 3.4 A		70	90	mΩ
		V _{GS} = 2.5 V, I _D :	= 1.7 A		95	120	1
Forward Transconductance	9FS	V _{DS} = 10 V, I _D = 3.4 A			6.7		S
Charges, Capacitances & Gate Resi	stance						
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz,	, V _{DS} = 10 V		144	275	pF
Output Capacitance	C _{OSS}				67	125	1
Reverse Transfer Capacitance	C _{RSS}				22	40	1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 10	V; I _D = 3.4 A		2.1	5.0	nC
Threshold Gate Charge	Q _{G(TH)}				0.11		
Gate-to-Source Charge	Q_{GS}				0.42		1
Gate-to-Drain Charge	Q_{GD}				0.7		1
Switching Characteristics, V _{GS} = 4.5	5 V (Note 6)						
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DD}	= 16 V,		4.8	10	ns
Rise Time	t _r	I _D = 3.4 A, R _G =	: 10 Ω		13.6	25	1
Turn-Off Delay Time	t _{d(OFF)}				9.0	20	1
Fall Time	t _f	1			1.9	5.0	1
Drain-Source Diode Characteristics	3						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 1.7 A T _J = 25°C			0.8	1.15	V
			T _J = 150°C		0.63		1
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V}, d_{ISD}/d_t =$	100 A/μs,		12		ns
Charge Time	t _a	I _S = 1.0 A			8.0		1
Discharge Time	t _b				4.0		1
Reverse Recovery Charge	Q _{RR}				5.0		nC

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2% 6. Switching characteristics are independent of operating junction temperatures

TYPICAL MOSFET I N-CHANNEL PERFORMANCE CURVES

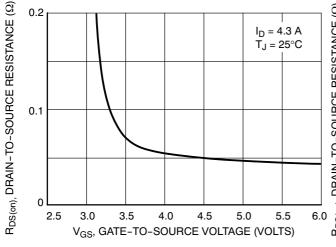
(T_J = 25°C unless otherwise noted)



10 9 $V_{DS} \ge 10 \text{ V}$ ID, DRAIN CURRENT (AMPS) 8 7 6 5 4 100°C 3 2 -55°C 0 1.5 2 2.5 3 3.5 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



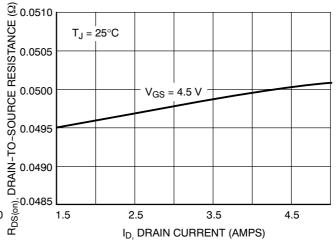
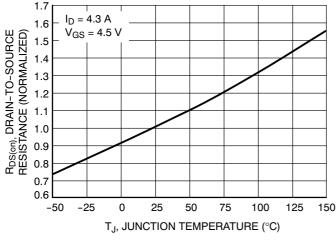


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



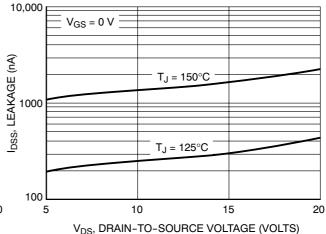


Figure 5. On-Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL MOSFET I N-CHANNEL PERFORMANCE CURVES

(T_{.1} = 25°C unless otherwise noted)

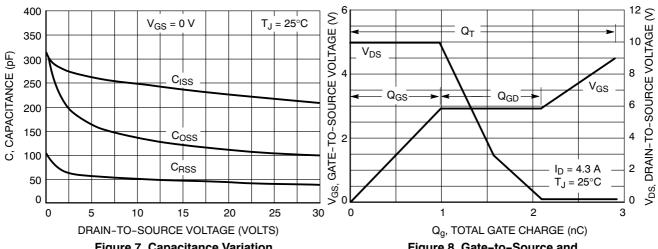


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

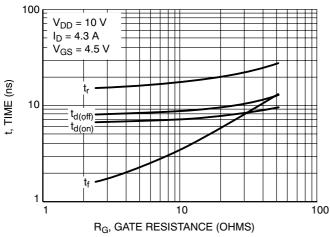


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

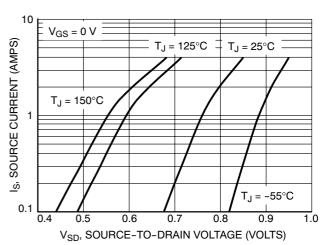


Figure 10. Diode Forward Voltage vs. Current

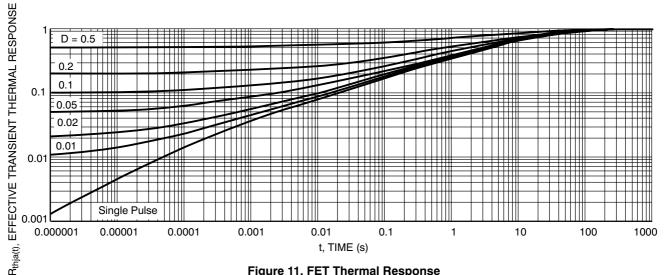
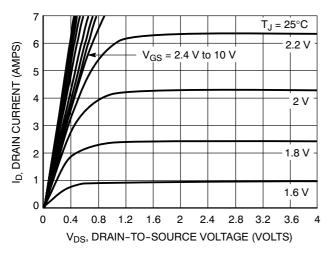


Figure 11. FET Thermal Response

TYPICAL MOSFET II N-CHANNEL PERFORMANCE CURVES

(T_J = 25°C unless otherwise noted)



V_{DS} ≥ 10 V

ONUME

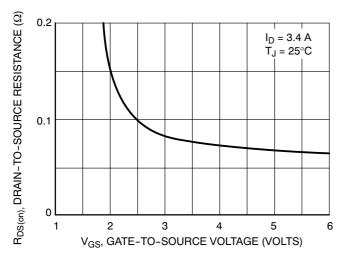
T_J = -55°C

1 1.5 2 2.5 3 3.5 4

V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 12. On-Region Characteristics

Figure 13. Transfer Characteristics



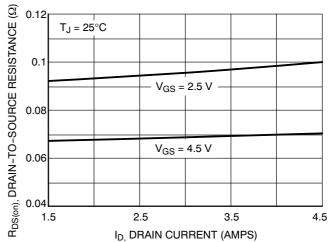
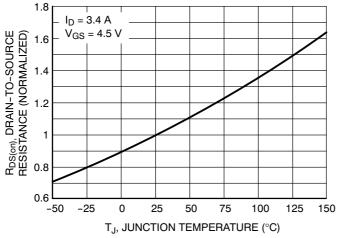


Figure 14. On-Resistance vs. Gate-to-Source Voltage

Figure 15. On-Resistance vs. Drain Current and Gate Voltage



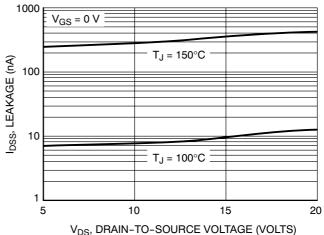


Figure 16. On–Resistance Variation with Temperature

Figure 17. Drain-to-Source Leakage Current vs. Voltage

TYPICAL MOSFET II N-CHANNEL PERFORMANCE CURVES

(T_{.1} = 25°C unless otherwise noted)

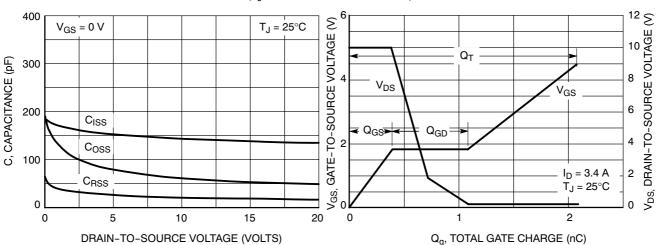


Figure 18. Capacitance Variation

Figure 19. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

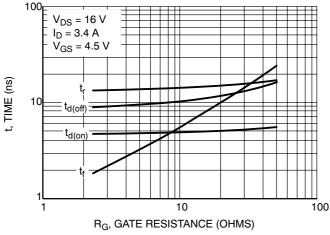


Figure 20. Resistive Switching Time Variation vs. Gate Resistance

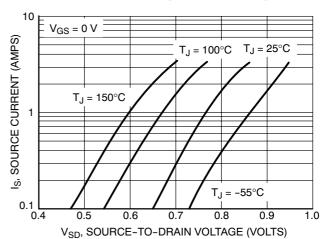


Figure 21. Diode Forward Voltage vs. Current

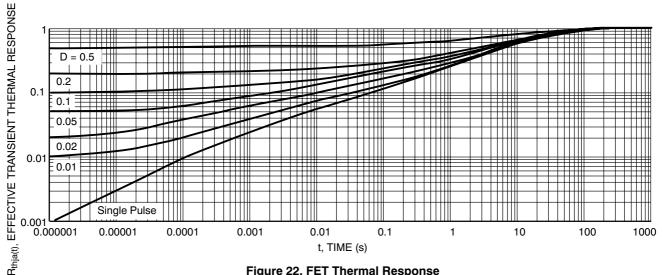
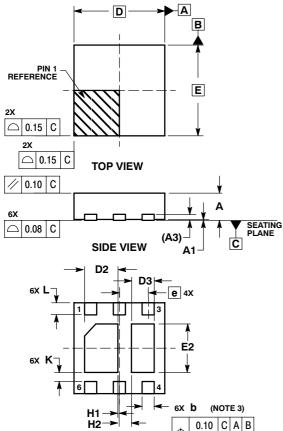


Figure 22. FET Thermal Response

PACKAGE DIMENSIONS

DFN6 3*3 MM, 0.95 PITCH

CASE 506AG-01 ISSUE O



Ф

BOTTOM VIEW

0.05 C

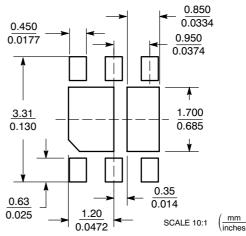
NOTES:

- 1. DIMENSIONS AND TOLERANCING PER ASME
- Y14.5M, 1994.

 CONTROLLING DIMENSION: MILLIMETERS.
- 3. DIMESNION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL.
- COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.80	0.90	1.00		
A1	0.00	0.03	0.05		
А3	0	.20 REF			
b	0.35	0.40	0.45		
D	3	.00 BSC	;		
D2	1.00	1.10	1.20		
D3	0.65	0.75	0.85		
E	3	.00 BSC	;		
E2	1.50	1.60	1.70		
е	0	.95 BSC			
K	0.21				
L	0.30	0.40	0.50		
H1	0.05 REF				
H2	0.40 REF				

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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